EE 330 Lecture 35

Telescopic Cascode OpAmp

Amplifier Biasing

Other Amplifier Structures

Frequency-Dependent Performance of Amplifiers

Parasitic Capacitances in MOS Devices

Spring 2024 Exam Schedule

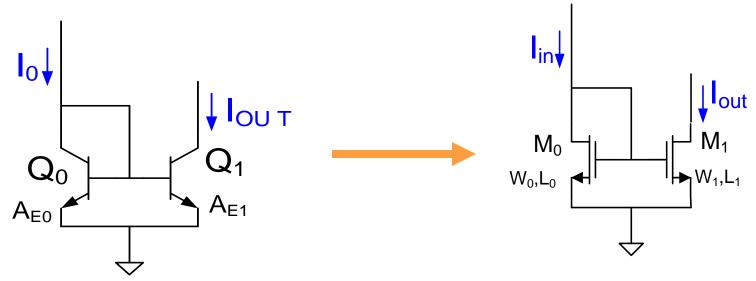
Exam 1 Friday Feb 16

Exam 2 Friday March 8

Exam 3 Friday April 19

Final Exam Tuesday May 7 7:30 AM - 9:30 AM

Current Sources/Mirrors Summary



npn Current Mirror

$$I_{out} = \left[\frac{A_{E1}}{A_{E0}} \right] I_{in}$$

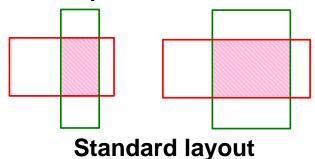
n-channel Current Mirror

$$\mathbf{I}_{out} = \left[\frac{\mathbf{W}_1}{\mathbf{W}_0} \frac{\mathbf{L}_0}{\mathbf{L}_1} \right] \mathbf{I}_{in}$$

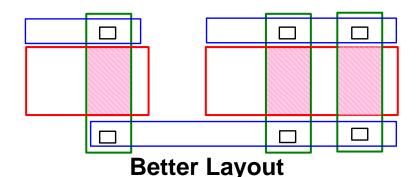
- Current mirror gain <u>can</u> be accurately controlled!
- Layout is important to get accurate gain (for both MOS and BJT)

Layout of Current Mirrors

Example with M = 2



$$M = \left[\frac{W_2}{W_1} \frac{L_1}{L_2} \right]$$



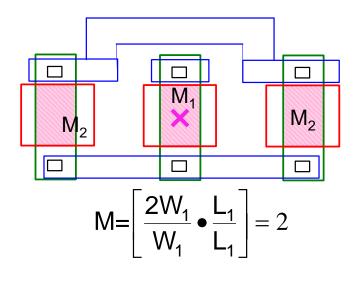
$$\mathsf{M} = \left\lceil \frac{2\mathsf{W}_1 + 4\Delta\mathsf{W}}{\mathsf{W}_1 + 2\Delta\mathsf{W}} \bullet \frac{\mathsf{L}_1 + 2\Delta\mathsf{L}}{\mathsf{L}_1 + 2\Delta\mathsf{L}} \right\rceil = 2$$

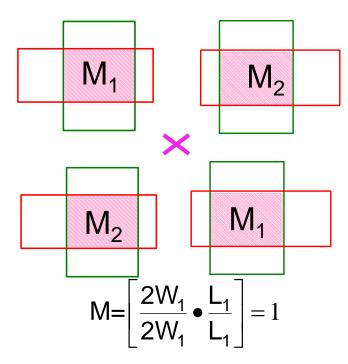
Even Better Layout

$$\mathsf{M} = \left\lceil \frac{2\mathsf{W}_1 + 4\Delta\mathsf{W}}{\mathsf{W}_1 + 2\Delta\mathsf{W}} \bullet \frac{\mathsf{L}_1 + 2\Delta\mathsf{L}}{\mathsf{L}_1 + 2\Delta\mathsf{L}} \right\rceil = 2$$

- This is termed a common-centroid layout
- Linear gradient mismatch eliminated with common-centroid layout!

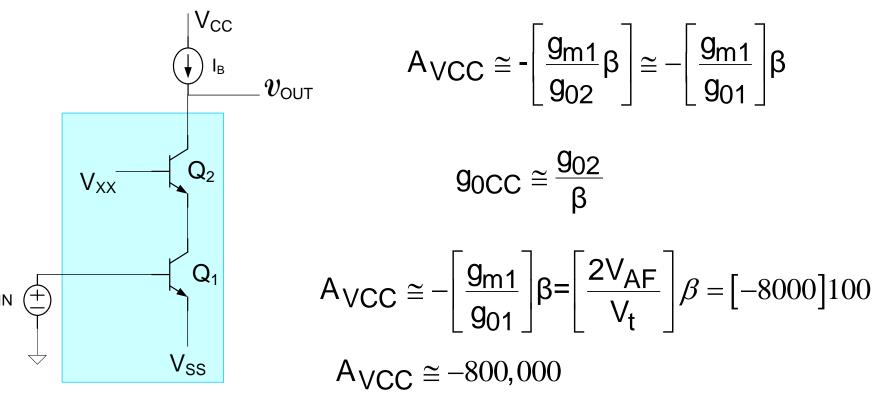
Common-Centroid Layouts





- Individual transistors often decomposed into parallel multiple unary devices connected in parallel
- Common-Centroid layout approach widely used to minimize (ideally cancel) gradient effects in matching-critical circuits
- Applications extend well beyond current mirrors
- More than 2 devices can share a common centroid



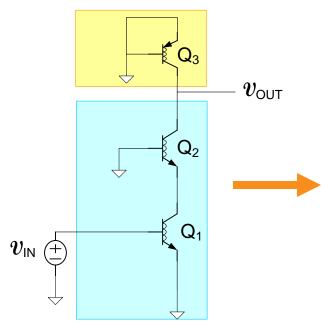


This gain is very large and only requires two transistors!

What happens to the gain if a transistor-level current source is used for I_B ?

Review From Previous Lecture

Cascode Configuration



$$A_{V} \cong A_{VCC} \left[\frac{g_{0CC}}{g_{03}} \right] \cong \frac{A_{VCC}}{\beta}$$

But recall

$$A_{VCC} \cong - \left[\frac{g_{m1}}{g_{01}} \right] \beta$$

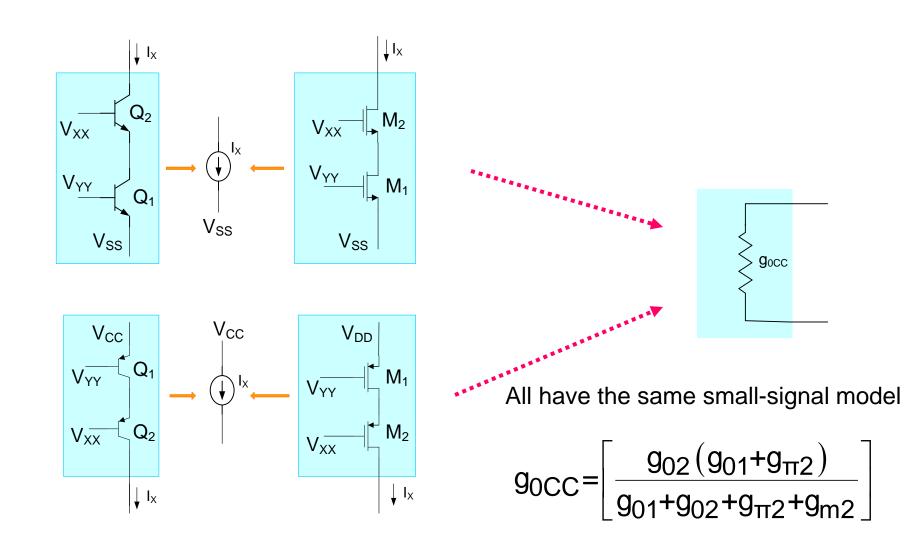
Thus

$$A_{V} \cong -\left[\frac{g_{m1}}{g_{01}}\right]$$

$$A_{V} \cong - \begin{bmatrix} I_{CQ} \\ V_{t} \\ I_{CQ} \\ V_{AF} \end{bmatrix} = - \begin{bmatrix} V_{AF} \\ V_{t} \end{bmatrix} \cong -8000$$

- This is still a factor of 2 better than that of the CE amplifier with transistor current source $A_{VCE} = -\left[\frac{g_{m1}}{2g_{01}}\right]$
- It only requires one additional transistor
- But its not nearly as good as the gain the cascode circuit seemed to provide

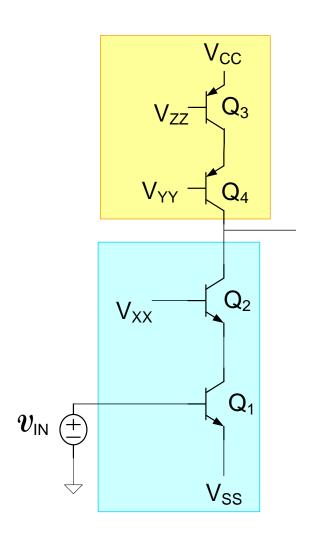
Cascode current sources



Review From Previous Lecture Cascode Configuration

 $v_{\scriptscriptstyle \mathsf{OUT}}$





$$A_{V} = - \left[\frac{g_{m1}}{g_{01}} \right] \frac{\beta}{2}$$

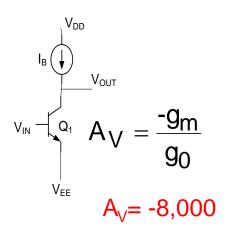
$$A_V = -[8000] \frac{100}{2} \cong -400,000$$

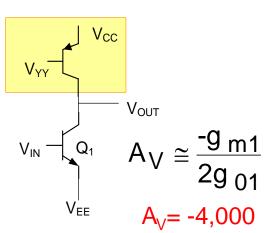
This gain is very large and is a factor of 2 below that obtained with an ideal current source biasing

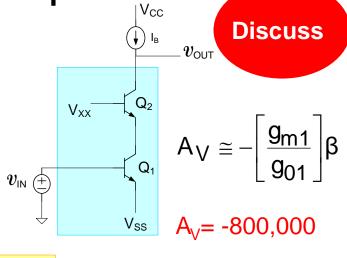
Although the factor of 2 is not desired, the performance of this circuit is still very good

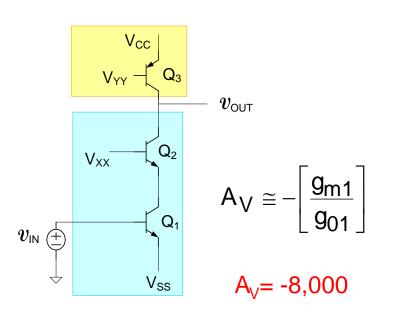
This factor of 2 gain reduction is that same as was observed for the CE amplifier when a transistorlevel current source was used

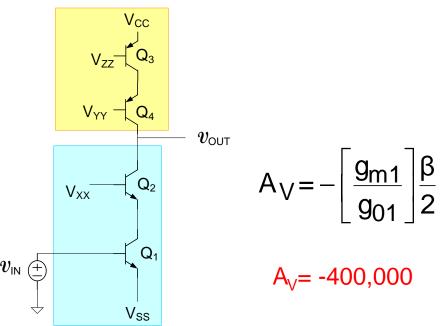
Cascode Configuration Comparisons





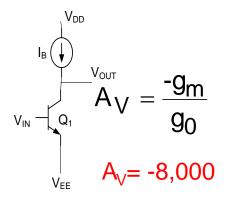


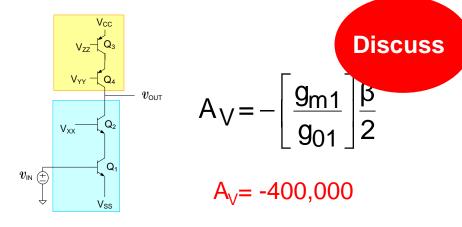


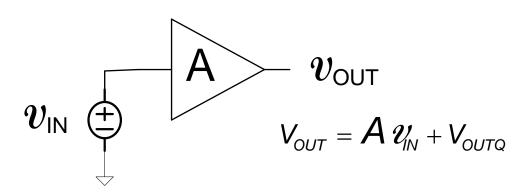


Can we use more cascoding to further increase the gain?

High Gain Amplifiers Seldom Used Open Loop





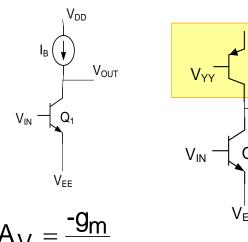


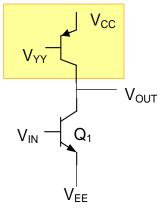
If A_V =-400,000 and V_{IN} increases by 1mV, what would happen at the output?

V_{OUT} would decrease by 400,000 x 1mV=-400V

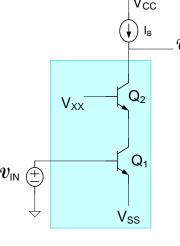
Review From Previous Lecture

High Gain Amplifier Comparisons (BJT)



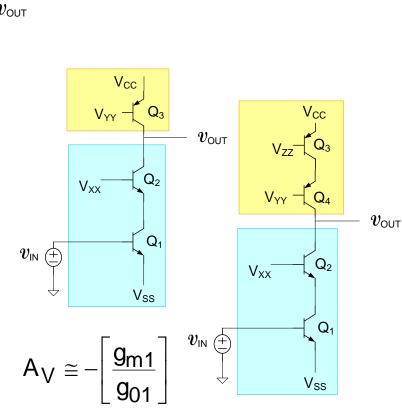


$$A_{V} \cong -\frac{1}{2} \frac{g_{m1}}{g_{01}}$$



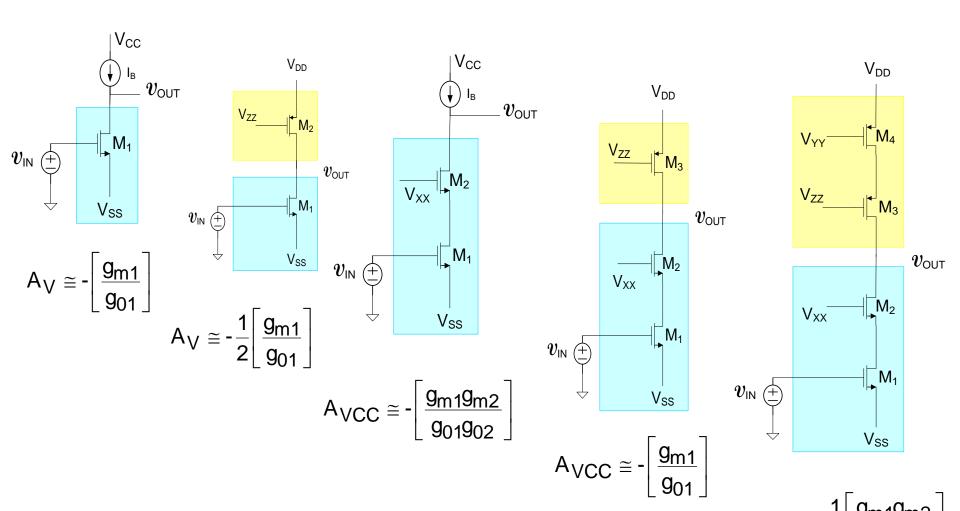
$$A_{V} \cong - \left[\frac{g_{m1}}{g_{01}}\right] \beta$$

- Single-ended high-gain amplifiers inherently difficult to bias (because of the high gain)
- Biasing becomes practical when used in differential applications
- These structures are widely used but usually with differential inputs



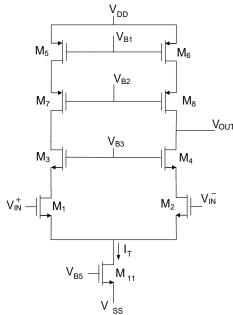
$$A_{V} = -\left[\frac{g_{m1}}{g_{01}}\right] \frac{\beta}{2}$$

High Gain Amplifier Comparisons (n-ch MOS)

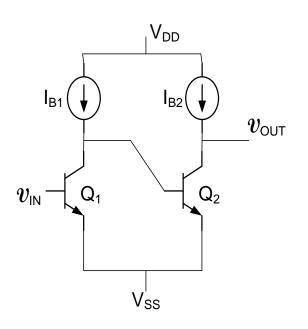


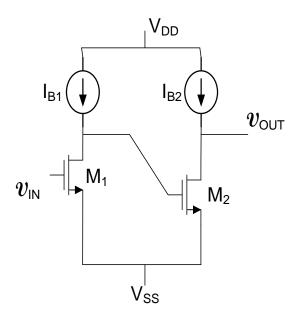
The Cascode Amplifier

- Operational amplifiers often built with basic cascode configuration
- CMFB used to address the biasing problem
- Usually configured as a differential structure when building op amps
- Have high output impedance (but can be bufferred)
- Terms "telescopic cascode", "folded-cascode", and "regulated cascode" often refer to op amps based upon the cascode configuration



Telescopic Cascode Op Amp (CMFB feedback biasing not shown)

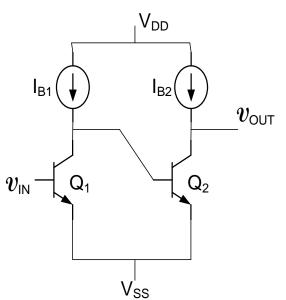


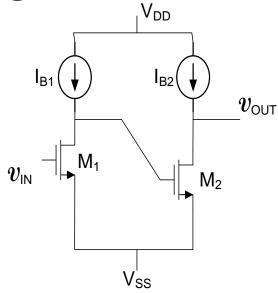


Two-stage CE:CE or CS:CS Cascade

$$A_{VCB} = ?$$

$$A_{VCM} = ?$$

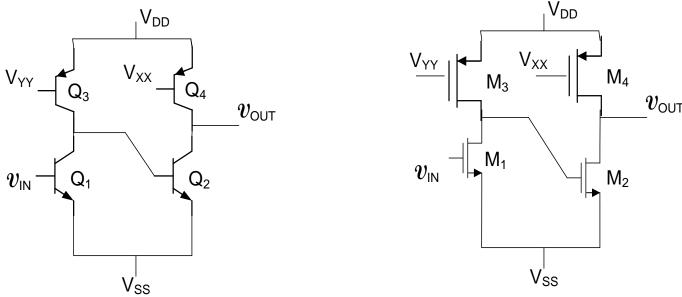




Two-stage CE:CE or CS:CS Cascade

$$\begin{aligned} A_{VCB} &\cong \left[\frac{-g_{m1}}{g_{01} + g_{\pi 2}} \right] \left[\frac{-g_{m2}}{g_{02}} \right] \cong \frac{g_{m1}g_{m2}}{g_{\pi 2}g_{02}} = \beta \frac{g_{m1}}{g_{02}} \\ A_{VCM} &= \left[\frac{-g_{m1}}{g_{01}} \right] \left[\frac{-g_{m2}}{g_{02}} \right] = \frac{g_{m1}g_{m2}}{g_{01}g_{02}} \end{aligned}$$

- Significant increase in gain
- Gain is noninverting
- Comparable to that obtained with the cascode but noninverting

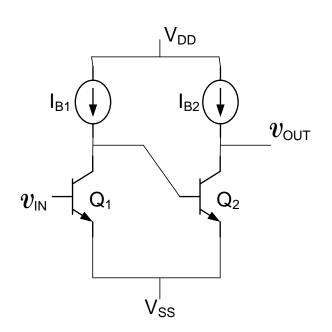


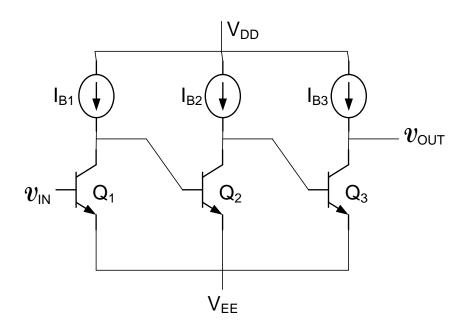
Two-stage CE:CE or CS:CS Cascade

$$A_{VCB} \cong \left[\frac{-g_{m1}}{g_{01} + g_{03} + g_{\pi 2}}\right] \left[\frac{-g_{m2}}{g_{02} + g_{04}}\right] \cong \frac{g_{m1}g_{m2}}{2g_{\pi 2}g_{02}} = \beta \frac{g_{m1}}{2g_{02}}$$

$$A_{VCM} = \left[\frac{-g_{m1}}{g_{01} + g_{03}}\right] \left[\frac{-g_{m2}}{g_{02} + g_{04}}\right] = \frac{g_{m1}g_{m2}}{4g_{01}g_{02}}$$

Note factor or 2 and 4 reduction in gain due to actual current source bias



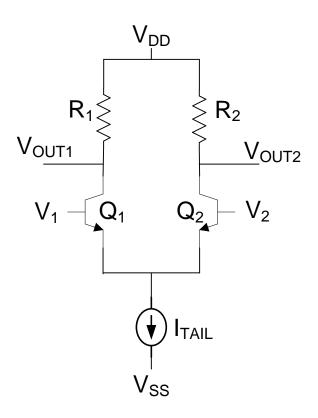


Two-stage CE Cascade

Three-stage CE Cascade

- Large gains can be obtained by cascading
- Gains are multiplicative (when loading is included)
- Large gains used to build "Op Amps" and feedback used to control gain value
- Some attention is needed for biasing but it is manageable
- Minor variant of the two-stage cascade often used to build Op Amps
- Compensation of two-stage cascade needed if feedback is applied to maintain stability
- For many years three or more stages were seldom cascaded because of challenges in compensation to maintain stability though recently some industrial adoptions

Differential Amplifiers



Basic operational amplifier circuit

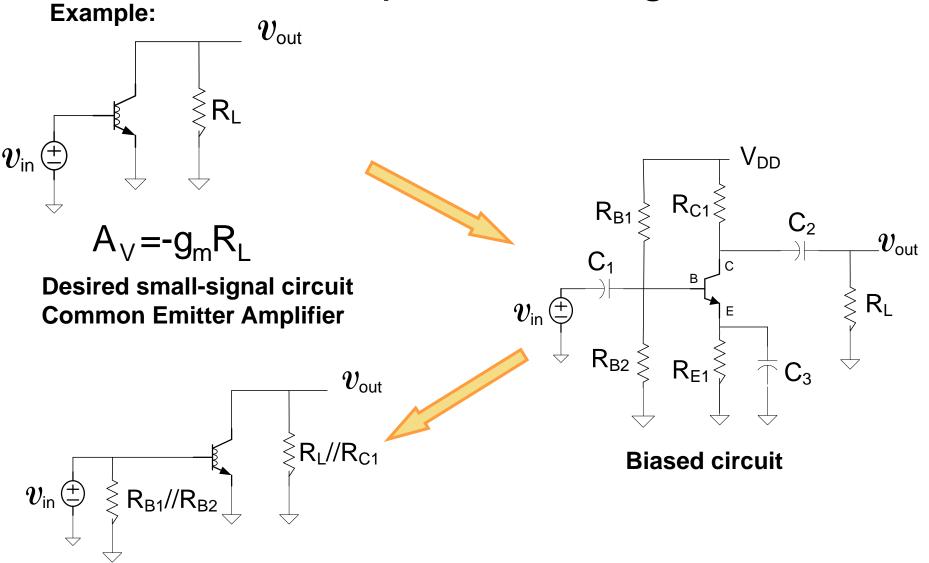
Amplifier biasing is that part of the design of a circuit that establishes the desired operating point (or Q-point)

Goal is to invariably minimize the impact the biasing circuit has on the small-signal performance of a circuit

Usually at most 2 dc power supplies are available and these are often fixed in value by system requirements – this restriction is cost driven

Discrete amplifiers invariable involve adding biasing resistors and use capacitor coupling and bypassing

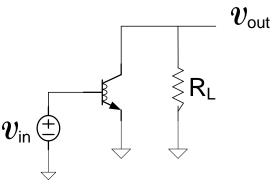
Integrated amplifiers often use current sources which can be used in very large numbers and are very inexpensive



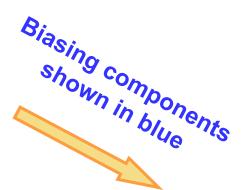
Actual small-signal circuit

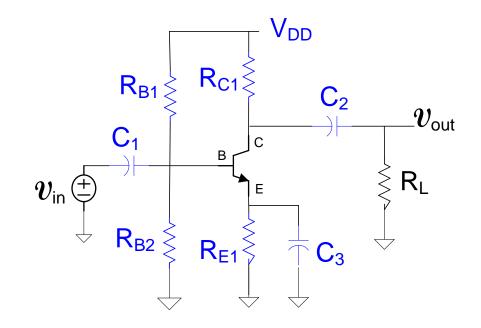
$$A_V = -g_m (R_L // R_{C1})$$

Example:



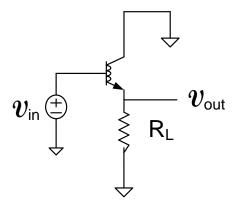
Desired small-signal circuit Common Emitter Amplifier



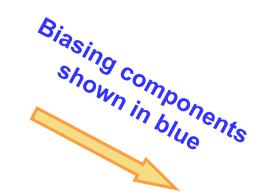


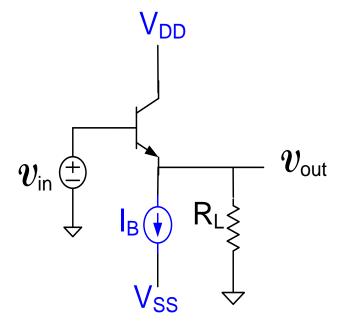
Biased small-signal circuit

Example:



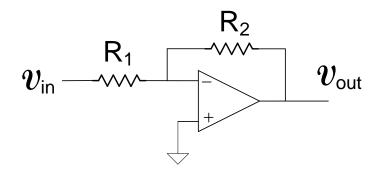
Desired small-signal circuit Common Collector Amplifier



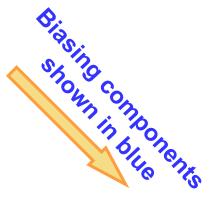


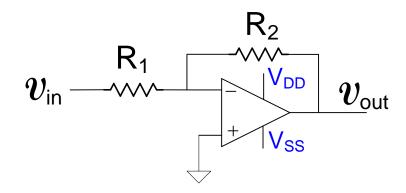
Biased circuit

Example:

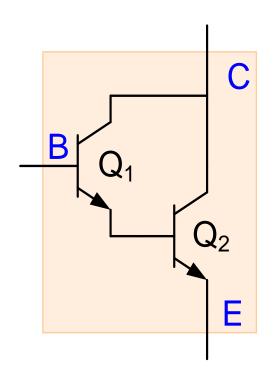


Desired small-signal circuit Inverting Feedback Amplifier

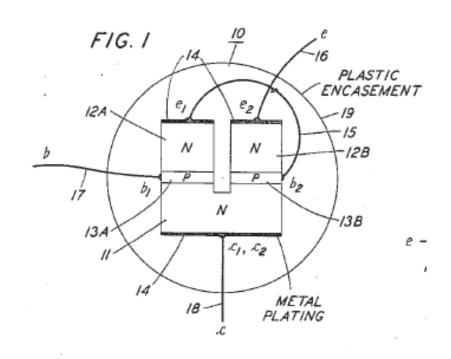




Biased circuit



Darlington Configuration



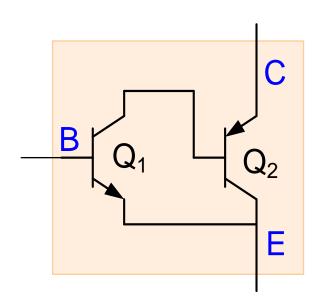
S. DARLINGTON

2,663,806

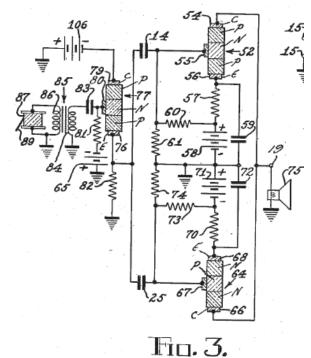
SEMICONDUCTOR SIGNAL TRANSLATING DEVICE

Filed May 9, 1952

- Current gain is approximately β²
- Two diode drop between B_{eff} and E_{eff}



Sziklai Pair



T.11.

May 7, 1957

G. C. SZIKLAI

2,791,644

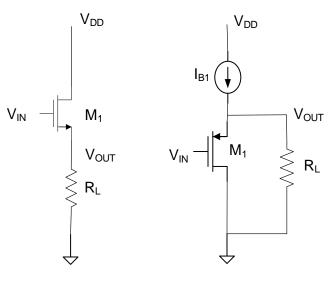
PUSH-PULL AMPLIFIER WITH COMPLEMENTARY TYPE TRANSISTORS

Filed Nov. 7, 1952

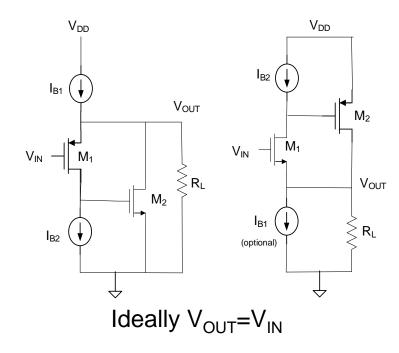
- Gain similar to that of Darlington Pair
- Current gain is approximately $\beta_n \beta_p$
- Current gain will not be as large when $\beta_p < \beta_n$
- Only one diode drop between B_{eff} and E_{eff}

Buffer

Super Buffer



Ideally V_{OUT}=V_{IN}

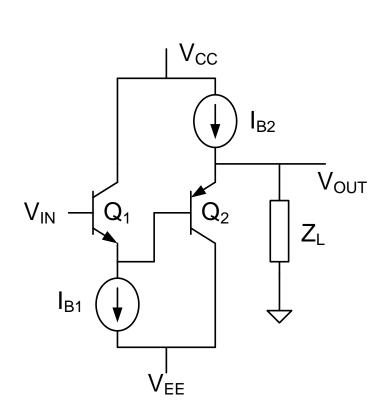


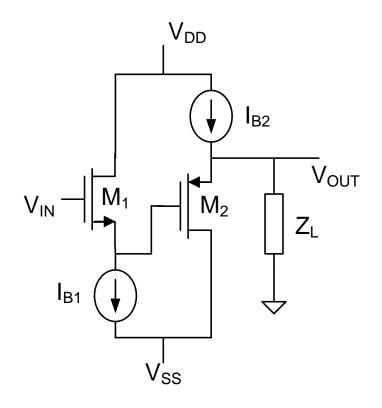
Assume load terminated on gnd

Current through shift transistor is constant for Super Buffer as $V_{\rm IN}$ changes so voltage shift does not change with $V_{\rm IN}$

Same nominal voltage shift as buffer

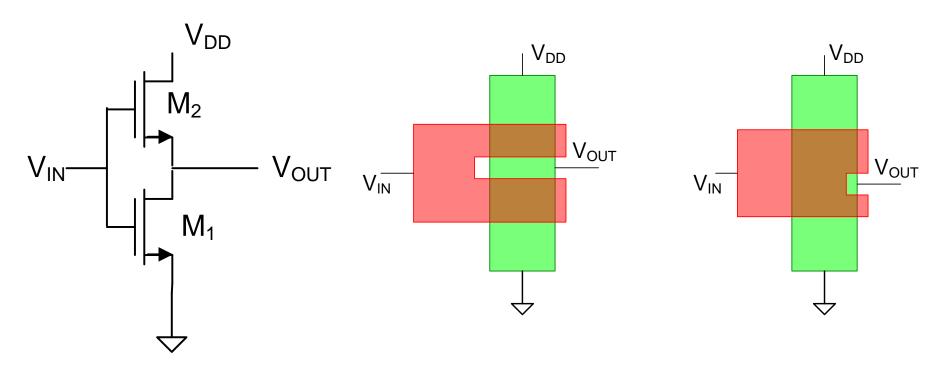
Low offset buffers





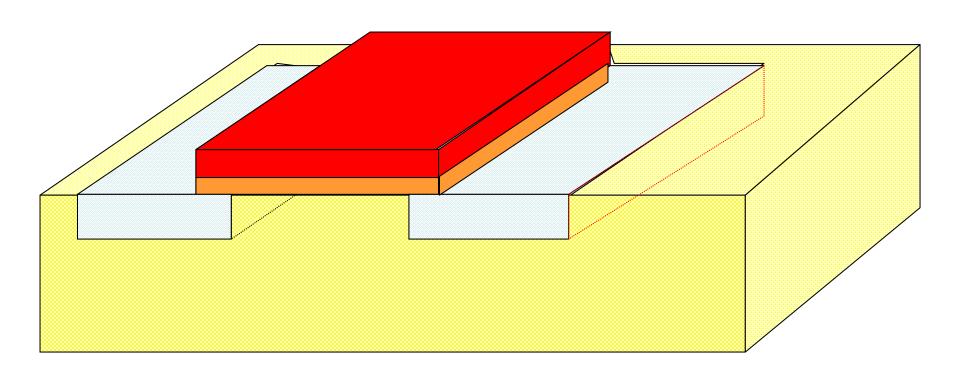
- Actually a CC-CC or a CD-CD cascade
- Significant drop in offset between input and output
- Biasing with DC current sources
- Can Add Super Buffer to Output

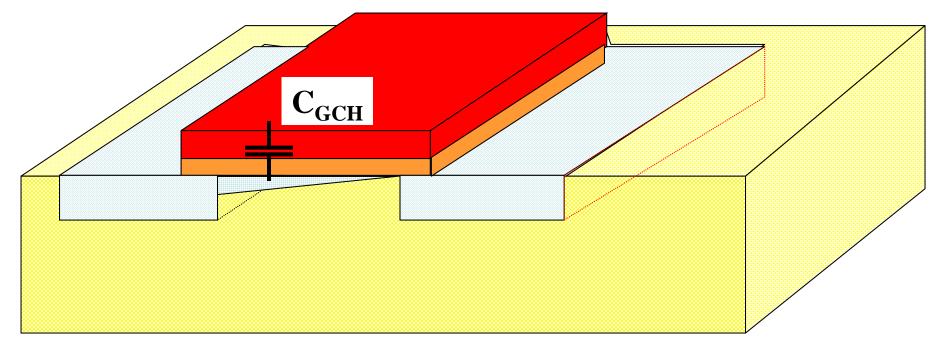
Voltage Attenuator



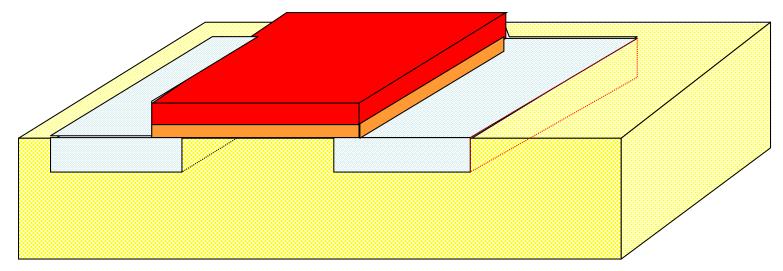
- Attenuation factor is quite accurate (Determined by geometry)
- Infinite input impedance
- M₁ in triode, M₂ in saturation
- Actually can be a channel-tapped structure

Frequency-Dependent Performance of Amplifiers

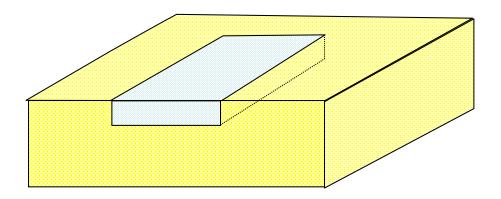




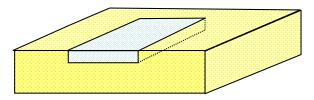
- This capacitance was modeled previously and exists when the transistor is operating in triode or saturation
- But there are others that also affect high-frequency or high-speed operation

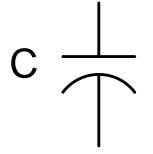


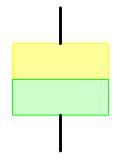
Recall that pn junctions have a depletion region!

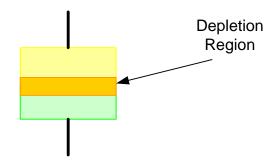


pn junction capacitance

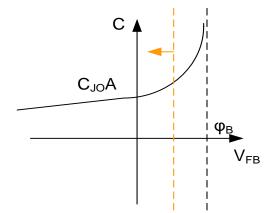






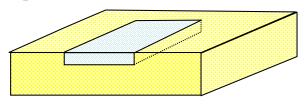


For $V_{FB} < \varphi_B/2$



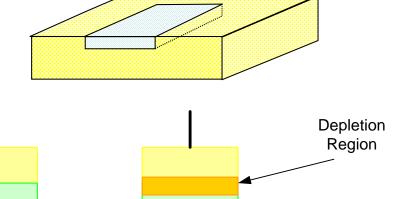
$$C = \frac{C_{J_0}A}{\left(1 - \frac{V_{FB}}{\phi_B}\right)^m}$$

pn junction capacitance



The bottom and the sidewall:

pn junction capacitance



For a pn junction capacitor

$$C_{\text{BOT}} = \frac{C_{\text{BOTO}}}{\left(1 - \frac{V_{\text{FB}}}{\phi_{\text{B}}}\right)^{\text{m}}} \qquad C_{\text{SW}} = \frac{C_{\text{SWO}}}{\left(1 - \frac{V_{\text{FB}}}{\phi_{\text{B}}}\right)^{\text{m}}}$$

A: Junction Area

P: Junction Perimeter

V_{FB}: forward bias on junction

Model Parameters:

 $\{C_{BOTO}, C_{SWO}, \phi_B, m\}$

C_{BOT} and C_{SW} are capacitance densities

Types of Capacitors in MOSFETs

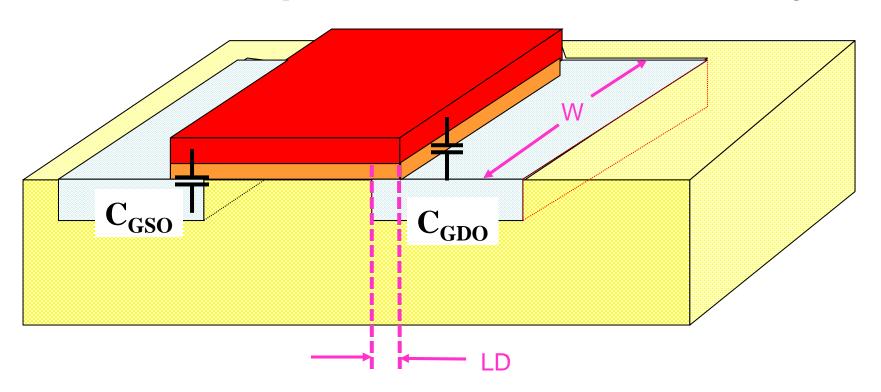
1. Fixed Capacitors



- a. Fixed Geometry
- b. Junction
- 2. Operating Region Dependent

Parasitic Capacitors in MOSFET

Fixed Capacitors – Fixed Geometry

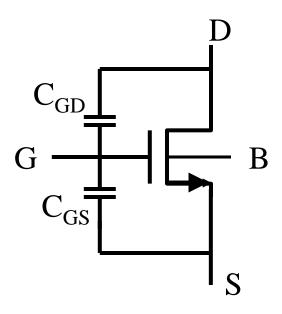


Overlap Capacitors: C_{GDO}, C_{GSO}

L_D: lateral diffusion

Cap Density: Cox

Parasitic Capacitance Summary (partial)



| | Cutoff | Ohmic | Saturation |
|------------------|--------------------|-----------|--------------------|
| C _{GSO} | CoxWL _D | $CoxWL_D$ | CoxWL _D |
| C_{GDO} | CoxWL _D | $CoxWL_D$ | CoxWL _D |

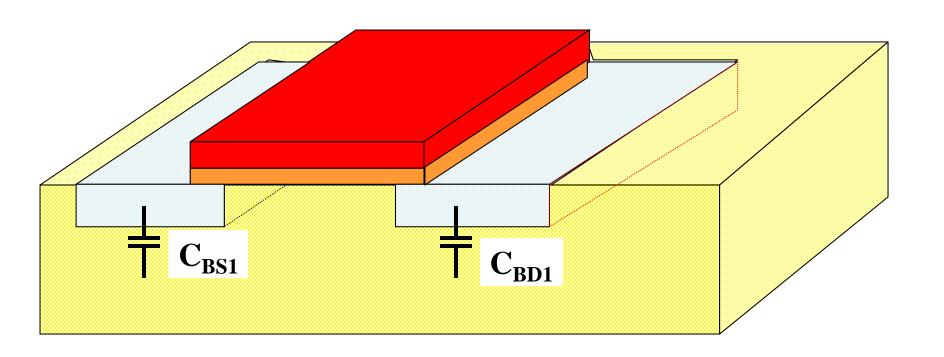
Overlap Capacitance Model Parameters

| CAPACITANCE PARAMETERS | | P+ I | | М1 | M2 | МЗ | M4 | M5 | M6 | R_W | D_N_W M51 | | UNITS |
|------------------------|-----|------|-------|----|----|----|----|----|----|-----|-----------|-----|---------|
| Area (substrate) | 942 | 1163 | 3 106 | 34 | 14 | 9 | 6 | 5 | 3 | | 123 | 125 | aF/um^2 |
| Area (N+active) | | | 8484 | 55 | 20 | 13 | 11 | 9 | 8 | | | | aF/um^2 |
| Area (P+active) | | | 8232 | | | | | | | | | | aF/um^2 |
| Area (poly) | | | | 66 | 17 | 10 | 7 | 5 | 4 | | | | aF/um^2 |
| Area (metal1) | | | | | 37 | 14 | 9 | 6 | 5 | | | | aF/um^2 |
| Area (metal2) | | | | | | 35 | 14 | 9 | 6 | | | | aF/um^2 |
| Area (metal3) | | | | | | | 37 | 14 | 9 | | | | aF/um^2 |
| Area (metal4) | | | | | | | | 36 | 14 | | | | aF/um^2 |
| Area (metal5) | | | | | | | | | 34 | | (| 984 | aF/um^2 |
| Area (r well) | 92(|) | | | | | | | | | | | aF/um^2 |
| Area (d well) | | | | | | | | | | 582 | | | aF/um^2 |
| Area (no well) | 137 | 7 | | | | | | | | | | | aF/um^2 |
| Fringe (substrate) | 212 | 2 23 | 35 | 41 | 35 | 29 | 21 | 14 | | | | | aF/um |
| Fringe (poly) | | | | 70 | 39 | 29 | 23 | 20 | 17 | | | | aF/um |
| Fringe (metal1) | | | | | 52 | 34 | | 22 | 19 | | | | aF/um |
| Fringe (metal2) | | | | | | 48 | 35 | 27 | 22 | | | | aF/um |
| Fringe (metal3) | | | | | | | 53 | 34 | 27 | | | | aF/um |
| Fringe (metal4) | | | | | | | | 58 | 35 | | | | aF/um |
| Fringe (metal5) | | | | | | | | | 55 | | | | aF/um |
| Overlap (N+active) | | | 89 | 5 | | | | | | | | | aF/um |
| Overlap (P+active) | | | 73 | 7 | | | | | | | | | aF/um |
| | | | | - | | | | | | | | | |

Types of Capacitors in MOSFETs

- 1. Fixed Capacitors
 - a. Fixed Geometry
- b. Junction
 - 2. Operating Region Dependent

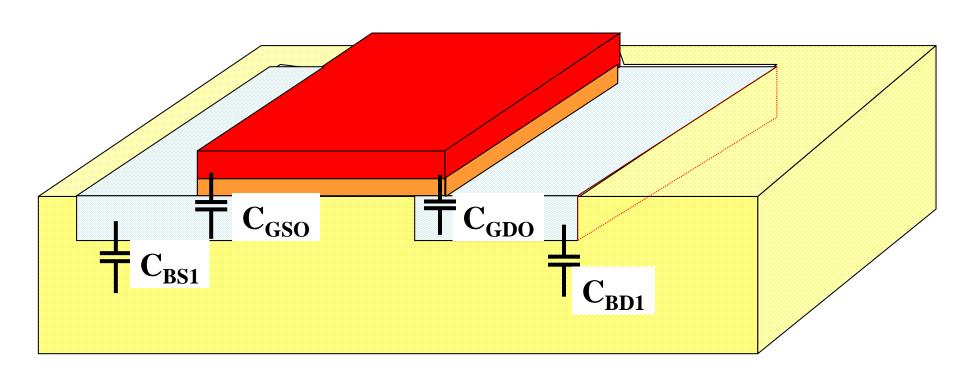
Parasitic Capacitors in MOSFET Fixed Capacitors- Junction



Junction Capacitors: C_{BS1}, C_{BD1}

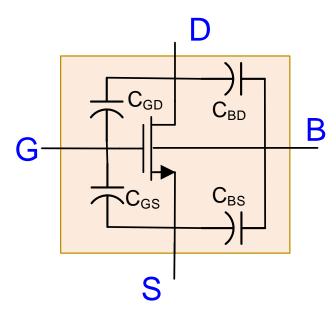
Parasitic Capacitors in MOSFET

- Fixed Capacitors



Overlap Capacitors: C_{GDO}, C_{GSO}

Junction Capacitors: C_{BS1}, C_{BD1}



C_{BOT} and C_{SW} are model parameters

| | Cutoff | Ohmic | Saturation |
|------------------|------------------------------------|------------------------------------|------------------------------------|
| C _{GSO} | CoxWL _D | CoxWL _D | $CoxWL_D$ |
| C_{GDO} | CoxWL _D | CoxWL _D | CoxWL _D |
| C _{BG} | | | |
| C _{BS} | $C_{BS1} = C_{BOT}A_S + C_{SW}P_S$ | $C_{BS1} = C_{BOT}A_S + C_{SW}P_S$ | $C_{BS1} = C_{BOT}A_S + C_{SW}P_S$ |
| C _{BD} | $C_{BD1} = C_{BOT}A_D + C_{SW}P_D$ | $C_{BD1} = C_{BOT}A_D + C_{SW}P_D$ | $C_{BD1} = C_{BOT}A_D + C_{SW}P_D$ |

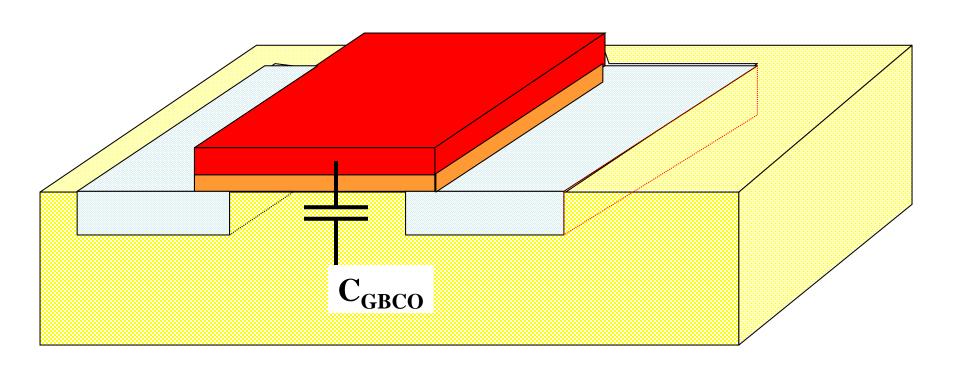
C_{BOT} and C_{SW} model parameters

| CAPACITANCE PARAMETERS N+ P+ POLY | M1 | M2 | МЗ | M4 | M5 | M6 | R W | D N W M5 | P N W | UNITS |
|-----------------------------------|----|----|----|----|----|----|-----|------------|-----------------|---------|
| Area (substrate) 942 1163 106 | 34 | 14 | 9 | 6 | 5 | 3 | _ | _ <u>_</u> | $\frac{-}{125}$ | aF/um^2 |
| Area (N+active) 8484 | 55 | 20 | 13 | 11 | 9 | 8 | | | | aF/um^2 |
| Area (P+active) 8232 | | | | | | | | | | aF/um^2 |
| Area (poly) | 66 | 17 | 10 | 7 | 5 | 4 | | | | aF/um^2 |
| Area (metal1) | | 37 | 14 | 9 | 6 | 5 | | | | aF/um^2 |
| Area (metal2) | | | 35 | 14 | 9 | 6 | | | | aF/um^2 |
| Area (metal3) | | | | 37 | 14 | 9 | | | | aF/um^2 |
| Area (metal4) | | | | | 36 | 14 | | | | aF/um^2 |
| Area (metal5) | | | | | | 34 | | ! | 984 | aF/um^2 |
| Area (r well) 920 | | | | | | | | | | aF/um^2 |
| Area (d well) | | | | | | | 582 | | | aF/um^2 |
| Area (no well) 137 | | | | | | | | | | aF/um^2 |
| Fringe (substrate) (212)(235) | 41 | 35 | 29 | 21 | 14 | | | | | aF/um |
| Fringe (poly) | 70 | 39 | 29 | 23 | 20 | 17 | | | | aF/um |
| Fringe (metal1) | | 52 | 34 | | 22 | 19 | | | | aF/um |
| Fringe (metal2) | | | 48 | 35 | 27 | 22 | | | | aF/um |
| Fringe (metal3) | | | | 53 | 34 | 27 | | | | aF/um |
| Fringe (metal4) | | | | | 58 | 35 | | | | aF/um |
| Fringe (metal5) | | | | | | 55 | | | | aF/um |
| Overlap (N+active) 895 | 5 | | | | | | | | | aF/um |
| Overlap (P+active) 73 | 7 | | | | | | | | | aF/um |

Types of Capacitors in MOSFETs

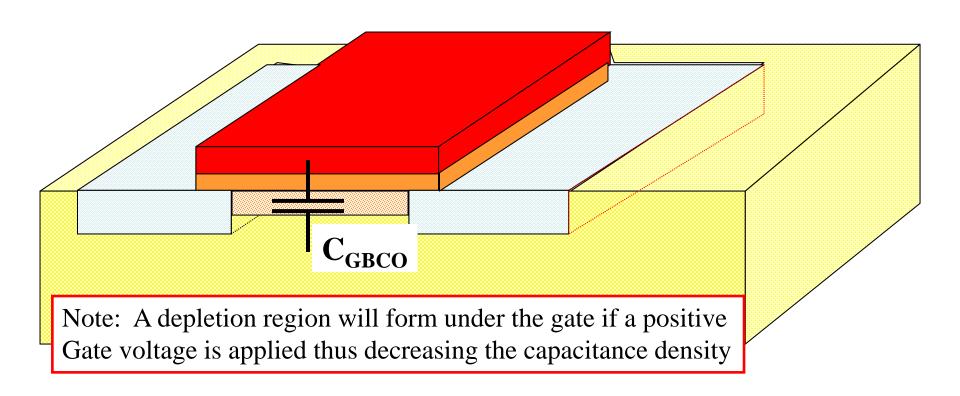
- 1. Fixed Capacitors
 - a. Fixed Geometry
 - b. Junction
- 2. Operating Region Dependent

Parasitic Capacitors in MOSFET Operation Region Dependent -- Cutoff



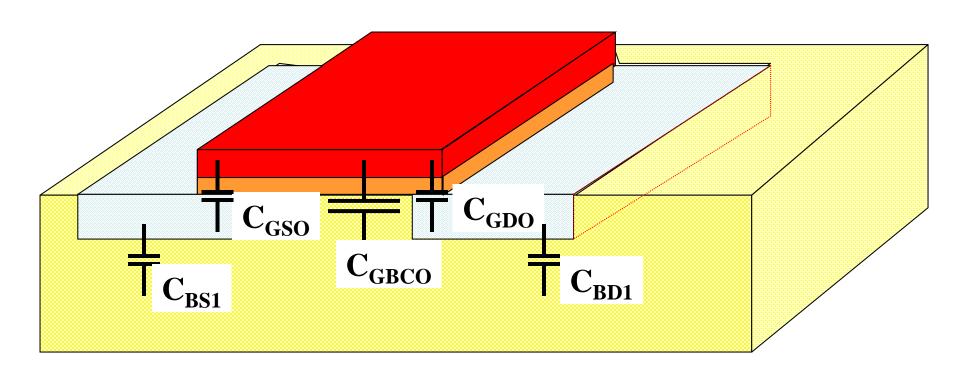
Cutoff Capacitor: C_{GBCO}

Parasitic Capacitors in MOSFET Operation Region Dependent -- Cutoff



Cutoff Capacitor: C_{GBCO}

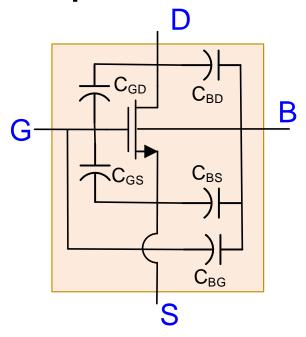
Parasitic Capacitors in MOSFET Operation Region Dependent and Fixed -- Cutoff



Overlap Capacitors: C_{GDO}, C_{GSO}

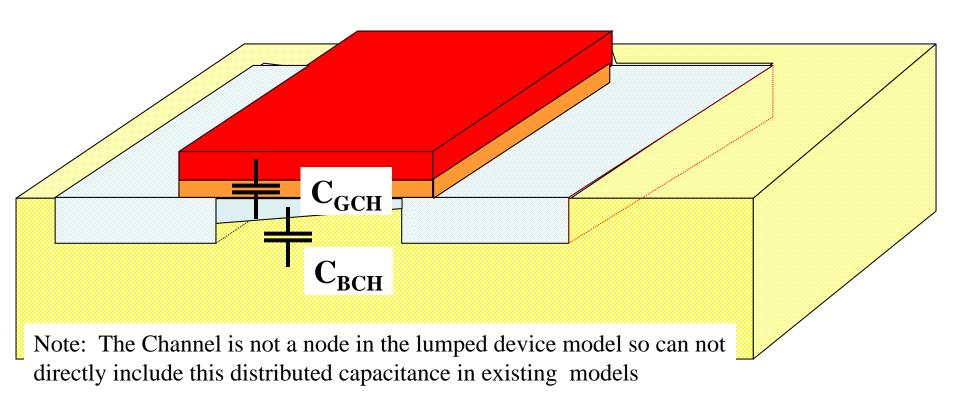
Junction Capacitors: C_{BS1}, C_{BD1}

Cutoff Capacitor: C_{GBCO}



| | Cutoff | Ohmic | Saturation |
|------------------|---|-------|------------|
| C _{GSO} | CoxWL _D | | |
| C_{GDO} | CoxWL _D | | |
| C _{BG} | CoxWL (or less) | | |
| C _{BS} | C _{BOT} A _S +C _{SW} P _S | | |
| C _{BD} | $C_{BOT}A_D+C_{SW}P_D$ | | |

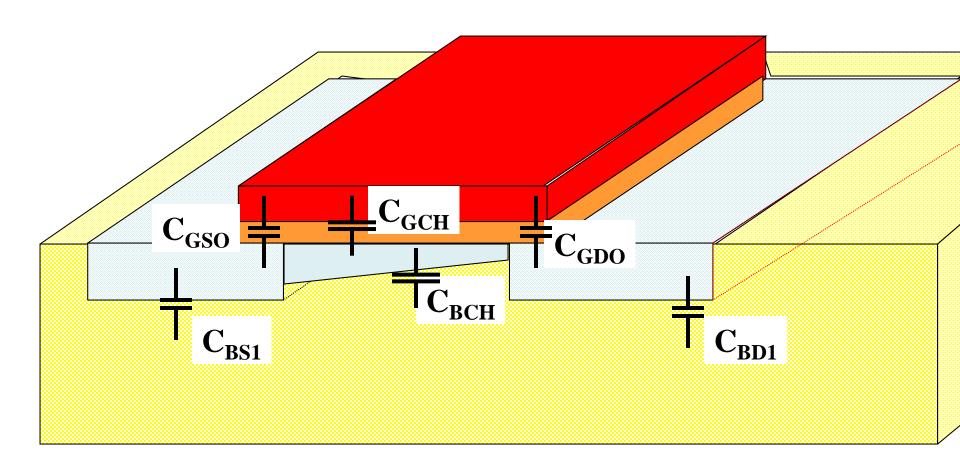
Parasitic Capacitors in MOSFET Operation Region Dependent -- Ohmic



Note: The distributed channel capacitance is usually lumped and split evenly between the source and drain nodes

Ohmic Capacitor: C_{GCH} , C_{BCH}

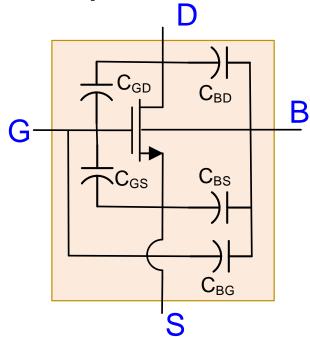
Parasitic Capacitors in MOSFET Operation Region Dependent and Fixed -- Ohmic



Overlap Capacitors: C_{GDO}, C_{GSO}

Junction Capacitors: C_{BS1}, C_{BD1}

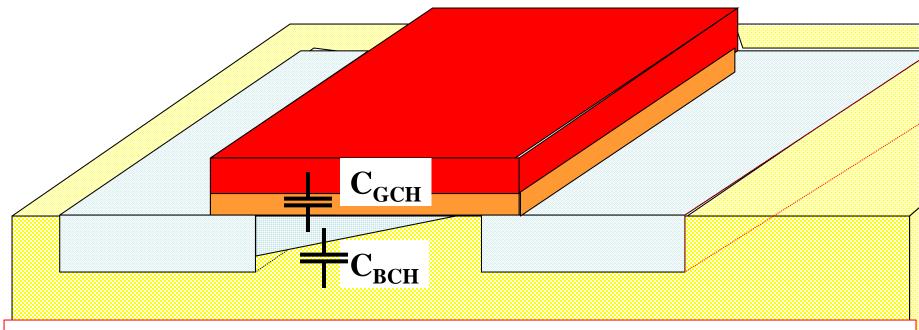
Ohmic Capacitor: C_{GCH}, C_{BCH}



Lumped C_{GC} and C_{BC} to analytically avoid dealing with distributed capacitance

| | Cutoff | Ohmic | Saturation |
|-----------------|--------------------------|--|------------|
| C _{GS} | CoxWL _D | 0.5CoxWL | |
| C_{GD} | CoxWL _D | 0.5CoxWL | |
| C _{BG} | CoxWL (or less) | 0 | |
| C _{BS} | $C_{BOT}A_S + C_{SW}P_S$ | C _{BOT} A _S +C _{SW} P _S +0.5WLC _{BOTCH} | |
| C _{BD} | $C_{BOT}A_D + C_{SW}P_D$ | C _{BOT} A _D +C _{SW} P _D +0.5WLC _{BOTCH} | |

Parasitic Capacitors in MOSFET Operation Region Dependent -- Saturation

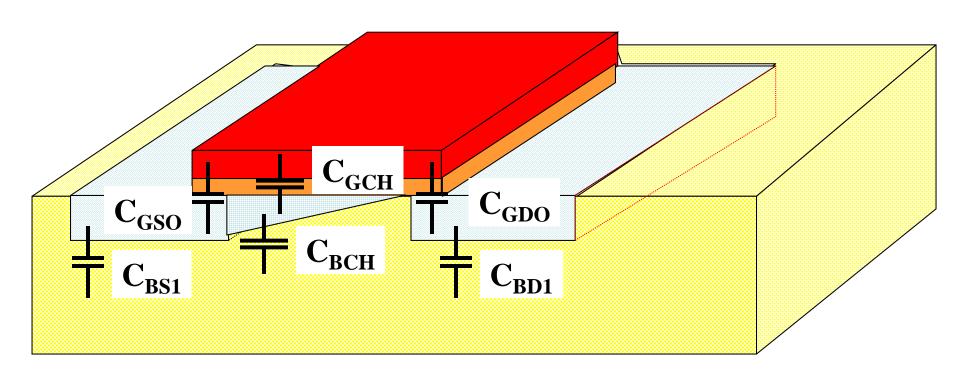


Note: Since the channel is an extension of the source when in saturation, the distributed capacitors to the channel are generally lumped to the source node

Saturation Capacitors: C_{GCH} , C_{BCH}

Parasitic Capacitors in MOSFET

Operation Region Dependent and Fixed -- Saturation

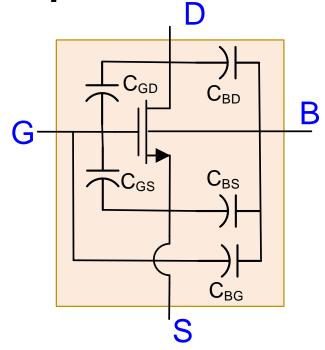


Overlap Capacitors: C_{GDO}, C_{GSO}

Junction Capacitors: C_{BS1}, C_{BD1}

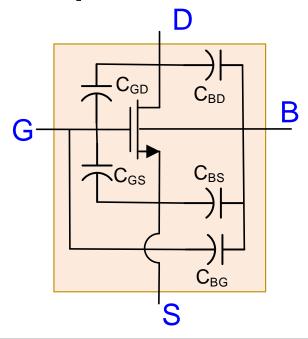
Saturation Capacitors: C_{GCH} , C_{BCH}

- 2/3 C_{OX}WL is often attributed to C_{GCH} to account for LD and saturation
- This approximation is reasonable for minimum-length devices but not so good for longer devices



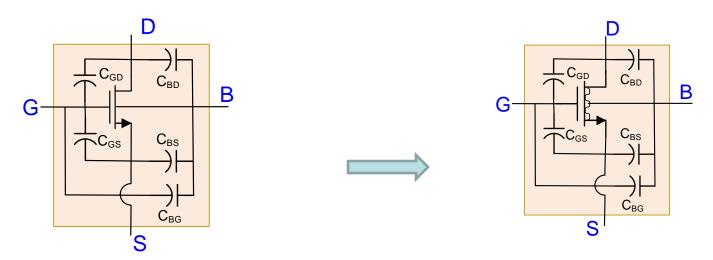
Lumped C_{GC} and C_{BC} to analytically avoid dealing with distributed capacitance

| | Cutoff | Ohmic | Saturation |
|-----------------|--------------------------|--|---|
| C _{GS} | CoxWL _D | 0.5C _{OX} WL | CoxWL _D +(2/3)C _{OX} WL |
| C _{GD} | CoxWL _D | 0.5C _{OX} WL | CoxWL _D |
| C _{BG} | CoxWL (or less) | 0 | 0 |
| C _{BS} | $C_{BOT}A_S+C_{SW}P_S$ | C _{BOT} A _S +C _{SW} P _S +0.5WLC _{BOTCH} | $C_{BOT}A_S+C_{SW}P_S+(2/3)WLC_{BOTCH}$ |
| C _{BD} | $C_{BOT}A_D + C_{SW}P_D$ | $C_{BOT}A_D+C_{SW}P_D+0.5WLC_{BOTCH}$ | $C_{BOT}A_D + C_{SW}P_D$ |



| | Cutoff | Ohmic | Saturation |
|-----------------|--------------------------|--|---|
| C _{GS} | CoxWL _D | 0.5C _{OX} WL | CoxWL _D +(2/3)C _{OX} WL |
| C _{GD} | CoxWL _D | 0.5C _{OX} WL | CoxWL _D |
| C _{BG} | CoxWL (or less) | 0 | 0 |
| C _{BS} | $C_{BOT}A_S + C_{SW}P_S$ | C _{BOT} A _S +C _{SW} P _S +0.5WLC _{BOTCH} | $C_{BOT}A_S+C_{SW}P_S+(2/3)WLC_{BOTCH}$ |
| C _{BD} | $C_{BOT}A_D + C_{SW}P_D$ | C _{BOT} A _D +C _{SW} P _D +0.5WLC _{BOTCH} | $C_{BOT}A_D + C_{SW}P_D$ |

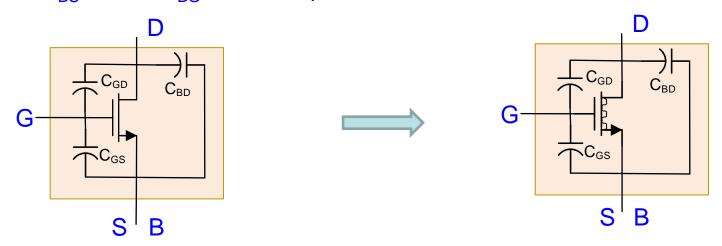
Observe there is no C_{DS} in this model because does not physically exist



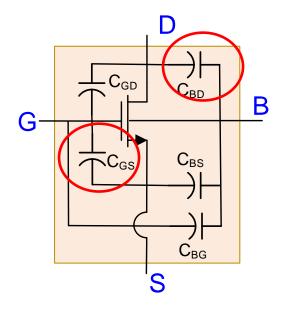
High Frequency Large Signal Model

High Frequency Small Signal Model

Often $V_{BS}=0$ and $C_{BG}=0$, so simplifies to



Parasitic Capacitance Implications



The parasitic capacitances inherently introduce an upper limit on how fast either digital circuits or analog circuits can operate in a given process

Two parameters, f_{MAX} and f_{T} , (not defined yet) are two metric that are used to specify the fundamental speed limit in a semiconductor process

The dominant parasitic capacitances for most circuits are C_{GS} and C_{BD}



Stay Safe and Stay Healthy!

End of Lecture 35